

Search Notes



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10/759,816

Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

BOEMMEL ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	492	2/05	hnh
439	493		
439	495		
439	496		
439	499		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
439/67 & 77 cursory	2/05	hnh